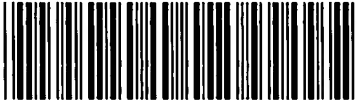


Search Notes 	Application/Control No. 10564389	Applicant(s)/Patent Under Reexamination TEEUW ET AL.
	Examiner Nguyen, Phong H	Art Unit 3724

SEARCHED			
Class	Subclass	Date	Examiner
30	346.53, 346.54, 50	6/11/07	pn
76	104.1		

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner